

Search Notes

Application/Control No.

10/776,646

Examiner

Young J. Kim

Applicant(s)/Patent under
Reexamination

FORSBERG ET AL.

Art Unit

1637

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
SEQ ID Numbers 11 and 12 Search conducted by STIC, searched issued-patent, published, and commercial databases	11/21/2006	YJK
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	11/21/2006	YJK